

**REMARKS**

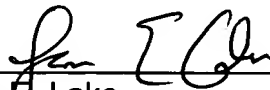
This Request for Continued Examination (RCE) Application is being filed in an abundance of caution to permit consideration of a Supplemental Information Disclosure Statement.

No new matter is being presented in this application.

A telephonic interview is requested in the event that the next office action is one other than a Notice of Allowance. The undersigned is available during normal business hours (Pacific Time Zone).

Respectfully submitted,

Dated: 08 Nov 2004

By:   
James E. Lake  
Reg. No. 44,854



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. .... 09/879,335  
Confirmation No. .... 4063  
Filing Date .... June 11, 2001  
Inventor .... Vishnu K. Agarwal, et al  
Assignee .... Micron Technology, Inc.  
Group Art Unit .... 2813  
Examiner .... C. Thompson  
Attorney's Docket No. .... MI22-1568  
Customer No. .... 021567  
Title: Capacitor Forming Methods and Capacitor Constructions

INFORMATION DISCLOSURE STATEMENT

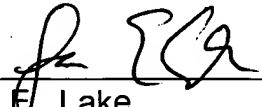
References -- See Attached Form PTO-1449

REMARKS

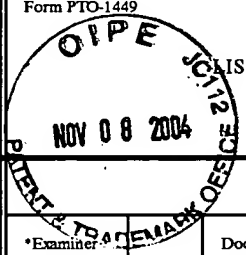
The citation listed may be material to the examination of the subject application and are therefore submitted in compliance with the duty of disclosure defined in 37 CFR §1.56. The Examiner is requested to make this citation of official record in this application. No admission is made regarding whether the submitted reference is prior art.

Respectfully submitted,

Dated: 08 Nov 2004

Attorney:   
James E. Lake  
Reg. No.: 44,854

EV372468330

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1568		SERIAL NO. 09/879,335	
 <b>LIST OF ART CITED BY APPLICANT</b> (Use several sheets if necessary)				APPLICANT Vishnu K. Agarwal et al			
				FILING DATE June 11, 2001		GROUP 2813	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	5,296,734	03/1994	Satoh			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes      No
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER				DATE CONSIDERED			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							